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8	CURRENT
4	CURRENTS
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10	FLOWS
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16	ТЕМР
17	TEMPERATURE
18	TEMPERATURES
19	TEMPS
70	THERMAL
21	THERMALS
22	((((ELECTROMIGRATION AND (CAPACITANCE SAME MATRIX)) AND (MATRIX SAME THERMAL)) AND ((FLOWING OR FLOW) SAME (CURRENT OR POWER))) AND (TEMPERATURE SAME (CURRENT OR POWER)))

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